



# Secondary ion mass spectrometry (SIMS)

The Laboratory of Structural Research and Materials Characterization

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### Facilities:

- CAMECA IMS SC Ultra


### Typical applications:

- Precise elemental analysis with sensitivity below 1 ppm.
- Depth profiling with subnanometer resolution.
- Lateral resolution of 1  $\mu\text{m}$ .
- 3D analysis.

RESEARCH NETWORK  
ŁUKASIEWICZ

 Institute of  
Electronic  
Materials  
Technology

 Wólczyńska 133,  
01-919 Warszawa

 +48 22 835 30 41  
+48 22 639 58 05

 [itme@itme.edu.pl](mailto:itme@itme.edu.pl)  
[komercjalizacja@itme.edu.pl](mailto:komercjalizacja@itme.edu.pl)